

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. FIS920020101US1		APPLICATION NO. 10/596,614		
				APPLICANT(S) Christopher Ausschnitt				
				FILING DATE 06/19/2006		GROUP ART UNIT N/A		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
		6,423,977	07/23/2002	Hayasaki, et al.				
		6,323,946	11/27/2001	Norton				
		5,968,691	10/19/1999	Yoshioka, et al.				
		5,363,171	11/08/1994	Mack				
		5,917,594	06/29/1999	Norton				
U.S. PATENT APPLICATION PUBLICATIONS								
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		6,451,621	09/17/2002	Rangarajan, et al.			
		6,433,871	08/13/2002	Lensing, et al.			
		5,631,721	05/20/1997	Stanton, et al.			
		5,965,309	10/12/1999	Ausschnitt, et al.			
		5,629,772	05/13/1997	Ausschnitt			

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		5,976,740	11/02/1999	Ausschnitt, et al.			
		5,880,838	03/09/1999	Marx, et al.			
		6,429,930	08/06/2002	Littau, et al.			
		6,432,729	08/13/2002	Mundt, et al.			
		6,051,349	04/18/2000	Yoshioka, et al.			

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		6,259,521	07/10/2001	Miller, et al.			
		6,388,253	05/14/2002	Su			
		6,429,943	08/06/2002	Opsal, et al.			
		5,739,909	04/14/1998	Blayo, et al.			
		6,383,824	05/07/2002	Lensing			

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		5,703,692	12/30/1997	McNeil, et al.			
		6,433,878	08/13,2002	Niu, et al.			
		6,485,891	11/26/2002	Noguchi, et al.			
		6,223,139	04/24/2001	Wong, et al.			

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0027648	03/07/2002	Van Der Laan, et al.			
		20030169423	09/11/2003	Finarov, et al.			
		20030155537	08/21/2003	Machavariani, et al.			
		20030086097	05/08/2003	Finarov			

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		6,171,731	01/09/2001	Medvedeva, et al.			
		5,916,711	06/29/1999	Salik, et al.			
		6,052,626	04/18/2000	Inui			
		6,263,299	07/17/2001	Aleshin, et al.			
		5,644,390	07/01/1997	Yasuzato			

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U.S. PATENT DOCUMENTS

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	5,867,276	02/02/1999	McNeil, et al.			
	5,559,601	09/24/1996	Gallatin, et al.			
	6,259,513	07/10/2001	Gallatin, et al.			
	5,712,707	01/27/1998	Ausschnitt, et al.			
	5,757,507	05/26/1998	Ausschnitt, et al.			

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		6,869,739	03/22/2005	Ausschnitt, et al.			
		6,183,919	02/06/2001	Ausschnitt, et al.			
		6,130,750	10/10/2000	Ausschnitt, et al.			
		6,879,400	04/12/2005	Ausschnitt, et al.			
		5,682,242	10/28,1997	Eylon			

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	5,517,312	05/14/1996	Finarov			
	6,704,920	03/09/2004	Brill, et al.			
	6,657,736	12/02/2003	Finarov, et al.			
	6,650,424	11/18/2003	Brill, et al.			
	6,643,017	11/04/2003	Cohen, et al.			

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		6,619,144	09/16/2003	Dvir			
		6,603,529	08/05/2003	Finarov			
		US RE38,153	06/24/2003	Finarov			
		6,556,947	04/29/2003	Scheiner, et al.			
		6,476,920	11/05/2002	Scheiner, et al.			

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		20020072003	06/13/2002	Brill, et al.			
		20020090744	07/11/2002	Brill, et al.			
		20020171828	11/21/2002	Cohen, et al.			
		20030058454	03/27/2003	Scheiner			

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		6,045,433	04/04/2000	Dvir, et al.				
		6,038,029	03/14/2000	Finarov				
		5,957,749	09/28/1999	Finarov				
		5,867,590	02/02/1999	Eylon				
		6,426,502	07/30/2002	Finarov				
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	6,424,417	07/23/2002	Cohen, et al.			
	6,407,809	06/18/2002	Finarov, et al.			
	6,368,181	04/09/2002	Dvir, et al.			
	6,292,265	09/18/2001	Finarov, et al.			
	6,281,974	08/28/2001	Scheiner, et al			

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		1) "Phi-Scatterometry for Integrated Linewidth Control in DRAM Manufacturing" Benesch, et al., 2001 IEEE 0-7803-6731 - June 2001 - pp 129 - 132 2) "Scatterometry Applied To Microelectronics Processing" John R. McNeil, 2000 IEEE, 0-7803-6252 - July 2000 pp. 37-38
		3) "Accuracy and Precision of Scatterometer Measurements Relative to Conventional CD Metrology" Hayes, et al., 2000 IEEE, 0-7803-6252- July 2000, pp. 39 - 40 4) "Distinguishing Dose From Defocus for In-Line Lithography Control" C.P. Ausschnitt, Part of the SPIE Conference on Metrology, Inspection & Process Control for Microlithography XIII, Santa Clara, CA, March 1999, SPIE Vol. 3677

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		6,166,801	12/26/2000	Dishon, et al.			
		6,100,985	08/08/2000	Scheiner, et al.			

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		20010026364	10/04/2001	Ravid, et al.			
		20020005957	01/17/2002	Finarov, et al.			
		20020033450	03/21/2002	Finarov, et al.			
		20010015811	08/23/2001	Ravid, et al.			

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			5) "Yield Prediction Using Critical Area Analysis With Inline Defect Data" Zhou, et al., 2002 IEEE/SEMI Advanced Semiconductor Manufacturing Conference, pp. 82 - 86
			6) "Specular Spectroscopic Scatterometry" Niu, et al., IEEE Transactions on Semiconductor Manufacturing, Vol. 14, No. 2, May 2001, pp. 97 - 111
			7) "Shallow Trench Isolation Scatterometry Metrology in a High Volume Fab" Lensing, et al., 2001 IEEE, 07803-6731- June 2001, pp 195 - 198
			8) "Full Profile Inter-layer Dielectric CMP Analysis" Chang, et al., 2001 IEEE, 0-7803-6731 - June 2001, pp. 133 - 136

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			9) "A New Approach To Pattern Metrology" C. Ausschnitt - Proc. SPIE 5375-7 - February 23, 2004, Santa Clara, CA - pp. 1 - 15

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